Machine and Deep Learning: Beyond Computational and Data-Related Limitations

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Message from the Guest Editors

Dear Colleagues,

This Special Issue aims to investigate innovative solutions to overcome two major obstacles in current AI technology: the lack of properly labeled data and the lack of storage and computational capacity on lightweight and embedded systems. We encourage authors to submit papers within different domains with or without industrial applications. This Special Issue aims to cover recent advances in DNN architecture compression and edge deployment on the one hand, and advances in unsupervised learning, self-/semi-supervised learning, multimodal learning, explainable deep learning, active learning and continuous learning on the other hand. Reviews and surveys on the state-of-the-art DNN architectures are also welcomed. The topics of interest for this Special Issue include:

- DNN software compression;
- DNN hardware compression;
- DNN pruning and quantization;
- Knowledge distillation;
- Model deployment in edge and cloud architectures;
- Edge artificial intelligence;
- Unsupervised learning;
- Semi-supervised and self-supervised learning;
- Active learning;
- Explainable deep learning;
- Continual learning;
- Knowledge transfer;
- Lifelong learning;

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Special Issue

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Message from the Editor-in-Chief

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